

**Cited in Papers - IEEE (2) | Other Publishers (0)**

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2. Mohamed Nour, Zeynep Çelik-Butler, Arif Sonnet, Fan-Chi Hou, Shaoping Tang, Guru Mathur, "A Stand-Alone Physics-Based Measurement-Driven Model and Simulation Tool for Random Telegraph Signals Originating From Experimentally Identified MOS Gate-Oxide Defects", *Electron Devices IEEE Transactions on*, vol. 63, no. 4, pp. 1428-1436, 2016.

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